

Search Notes

Application/Control No.

10/568,947

Examiner

Hai H. Huynh

Applicant(s)/Patent under
Reexamination

MUTO ET AL.

Art Unit

3747

SEARCHED

Class	Subclass	Date	Examiner
123	399	4/4/2007	HHH
123	350	4/4/2007	HHH
123	90.11	4/4/2007	HHH
123	90.15	4/4/2007	HHH
123	90.16	4/4/2007	HHH
123	90.17	4/4/2007	HHH
123	568.11	4/4/2007	HHH
123	568.14	4/4/2007	HHH
73	117.3	4/4/2007	HHH
73	118.2	4/4/2007	HHH
701	106	4/4/2007	HHH
701	110	4/4/2007	HHH
701	115	4/4/2007	HHH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East	4/4/2007	HHH